

**Search Notes**

Application/Control No.

10/768,319

Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

PELAEZ ET AL.

Art Unit

2683

**SEARCHED**

Class	Subclass	Date	Examiner
455	412.2	12/26/2005	CH
455	412.1	12/26/2005	CH
455	413	12/26/2005	CH
455	414.1	12/26/2005	CH
455	419	12/26/2005	CH
455	418	12/26/2005	CH
455	420	12/27/2005	CH
710	73	12/27/2005	CH
710	212	12/27/2005	CH
709	206	12/27/2005	CH
455	556	1/3/2005	CH
455	557	1/4/2005	CH
455	566	1/4/2005	CH
455	415	1/4/2005	CH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass and also combined with text	12/27/2005	CH
Combined critical Text search	12/26/2005	CH
Talked to Edan Orgad	12/27/2005	CH
Class 379/ 88.12,88.13,88.16,88.18	1/4/2005	CH